

Cantilever Data	Value	Range*
Resonance Frequency	14 kHz	10 - 19 kHz
Force Constant	0.2 N/m	0.06 - 0.38 N/m
Length	450 $\mu\text{m}$	445 - 455 $\mu\text{m}$
Mean Width	45 $\mu\text{m}$	40 - 50 $\mu\text{m}$
Thickness	2 $\mu\text{m}$	1.5 - 2.5 $\mu\text{m}$

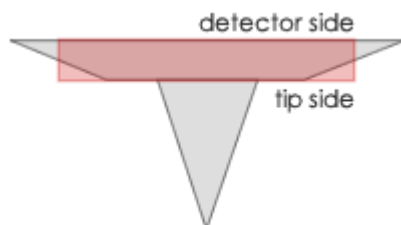
### Optimized positioning through maximized AFM tip visibility

NanoWorld® Arrow™ CONT probes are designed for Contact Mode imaging. Furthermore this type can be used for Force Distance Spectroscopy Mode or Pulsed Force Mode (PFM). The CONT type is optimized for high sensitivity due to a low Force Constant.

All SPM and AFM probes of the Arrow™ series are made from monolithic silicon which is highly doped to dissipate static charge. They are chemically inert and offer a high mechanical Q-factor for high sensitivity. These AFM probes feature a rectangular AFM cantilever with a triangular free end and a tetrahedral AFM tip with a typical height of 10 - 15  $\mu\text{m}$ .

Additionally, this AFM probe offers a AFM tip radius of curvature of less than 10 nm.

**The unique Arrow™ shape with the AFM tip position at the very end of the AFM cantilever allows easy positioning of the AFM tip on the area of interest.**



A trapezoidal cross section of the AFM cantilever and therefore 30% wider (e.g. NCH) AFM cantilever detector side result in easier and faster laser adjustment. Additionally, because there is simply more space to place and reflect the laser beam, a higher SUM signal is reached.

Tip shape: Arrow

Coating: none

Order Code	Quantity	Data Sheet
<b>ARROW-CONT-10</b>	<b>10</b>	Nominal values
<b>ARROW-CONT-20</b>	<b>20</b>	Nominal values
<b>ARROW-CONT-50</b>	<b>50</b>	Nominal values
<b>ARROW-CONT-W</b>	<b>380</b>	Nominal values